

U.S. Department of Commerce, Patent and Trademark Office		Docket No.: <b>AM-6265.D1</b>						
<i>O I P E 6 C I S E</i> DEC 08 2003 U.S. PATENT & TRADEMARK OFFICE		Serial No.: <b>10/646,014</b>						
LIST OF RELEVANT ART CITED BY APPLICANT (Use several sheets if necessary)		Applicant: <b>Peijun DING et al.</b>						
		Filing Date: <b>August 22, 2003</b>						
		Group: <b>Unknown 1753</b>						
<b>U.S. PATENT DOCUMENTS</b>								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>SHV</i>	AA	4,871,433	10/03/89	Wagner et al.	204	192.12		
<i>SHV</i>	AB	5,133,825	07/28/92	Hakamata et al.	156	345		
<i>SHV</i>	AC	5,178,739	01/12/93	Barnes et al.	204	192.12		
<i>SHV</i>	AD	5,482,611	01/09/96	Helmer et al.	204	298.17		
<i>SHV</i>	AE	5,593,551	01/14/97	Lai	204	192.12		
<i>SHV</i>	AF	5,733,405	03/31/98	Taki et al.	156	345		
<i>SHV</i>	AG	5,907,220	05/25/99	Tepman et al.	315	111.41		
<i>SHV</i>	AH	6,014,943	01/18/00	Arami et al.	118	723 E		
<i>SHV</i>	AI	6,077,403	06/20/00	Kobayashi et al.	204	192.12		
<i>SHV</i>	AJ	6,159,351	12/12/00	J'Afer et al.	204	298.19		
<i>SHV</i>	AK	6,163,006	12/19/00	Doughty et al.	219	121.43		
<b>FOREIGN PATENT DOCUMENTS (Translation)</b>								
		Document Number	Date	Country	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>								
	AR							
	AS							
	AT							
Examiner	<i>SHV</i>	Date Considered	<i>May 6 2004</i>					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								

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U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
SHV	AA	6,179,973	01/30/01	Lai et al.	204	192.12		
SHV	AB	6,193,854	02/27/01	Lai et al.	204	192.12		
SHV	AC	6,290,825	09/18/01	Fu	204	298.2		
SHV	AD	6,352,629	03/05/02	Wang	204	298.2		
SHV	AE	6,413,383	07/02/02	Chiang et al.	204	192.13		
SHV	AF	6,423,192	07/23/02	Wada et al.	204	192.12		
SHV	AG	US/2003/0089601	05/15/03	Ding et al.	204	298.2	11/14/01	
FOREIGN PATENT DOCUMENTS (Translation)								
		Document Number	Date	Country	Class	Subclass	Yes	No
SHV	AH	0 653 776	5/17/95	Europe	H01J	37/34	X	
SHV	AI	EP 1 091 016	4/11/01	Europe	C23C	14/35	X	
SHV	AJ	EP 1 119 017	7/25/01	Europe	H01J	37/34	X	
SHV	AK	EP 1 174 902	01/23/02	Europe	H01J	37/34	X	
SHV	AL	WO 00/05745	02/03/00	PCT	H01J	37/34	X	
SHV	AM	WO 02/11176	02/07/02	PCT	H01J	37/34	X	
SHV	AN	WO 02/37528	05/10/02	PCT	H01J	37/34	X	
SHV	AO	10204614	08/04/98	Japan	C23C	14/00	Abstract	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
SHV	AR	Ashtiani et al., "A new hollow-cathode magnetron source for 0.10µm copper applications", 0-7803-6327-2, 2000, pp. 37-39						
	AS							
	AT							
Examiner		Date Considered 11/6/2004						
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